

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/685,560	CHOU ET AL.
Examiner	Art Unit	
Sam K. Ahn	2611	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	all sublasses	3/14	an
370, 379			
455, 708	above	3/14	an